Multispectral Imaging for Materials Analysis

Steven A. Buntin

Group Leader
Surface and Interface Research Group
Chemical Science and Technology Laboratory
National Institute of Science and Technology
Gaithersburg, MD

Measurement paradigms – materials analysis:

1) Serial:

- throughput (significantly) enhanced by automation/scanning.
- e.g., mass spec, chromatography screening.

2) Parallel:

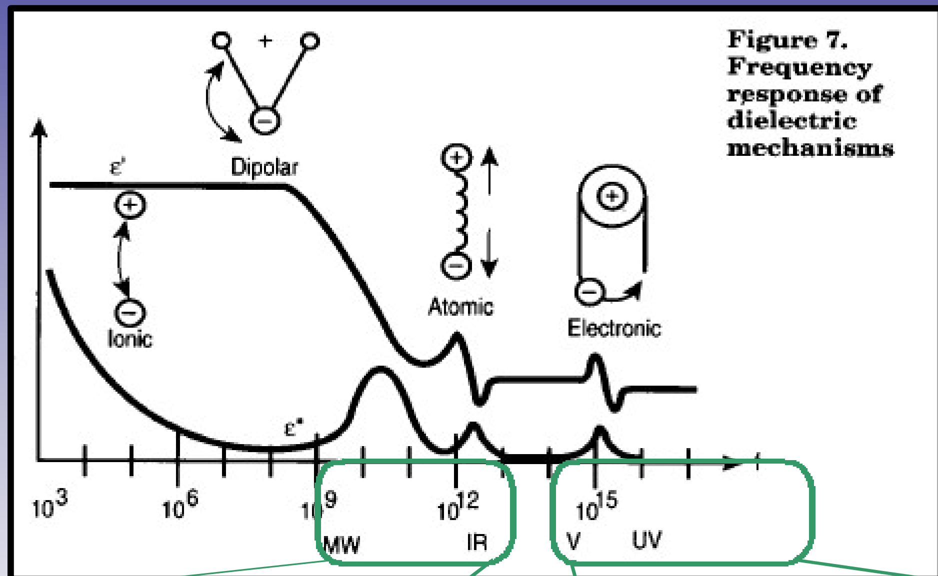
- 2D array-based detection "views" entire library.
- e.g., IR thermography, hyperspectral imaging, anode-array REMPI.

• **Multitasking:**

- data on two or more distinct system properties using a single integrated measurement platform.
- serial or parallel based techniques.
- e.g., CCD-based detection of selective oxidation of naphthalene:
  LIF – reaction product; NIR emission – thermography
  *(H. Su and E.S. Yeung; JACS **122**, 7422, '00; H. Su, Y. Hou, R.S. Houk, G.L. Schrader and E.S. Yeung, Anal. Chem. **73**, 4434, '01)*

Multitasking Probe: motivation and systems.

- Single instrument platform: materials performance and properties.
- Dielectric thin films.



Targeted performance frequency range:

➢High-ε mat'l: DRAM, capacitors, …

➢Low-ε mat'l: next-generation Si, …

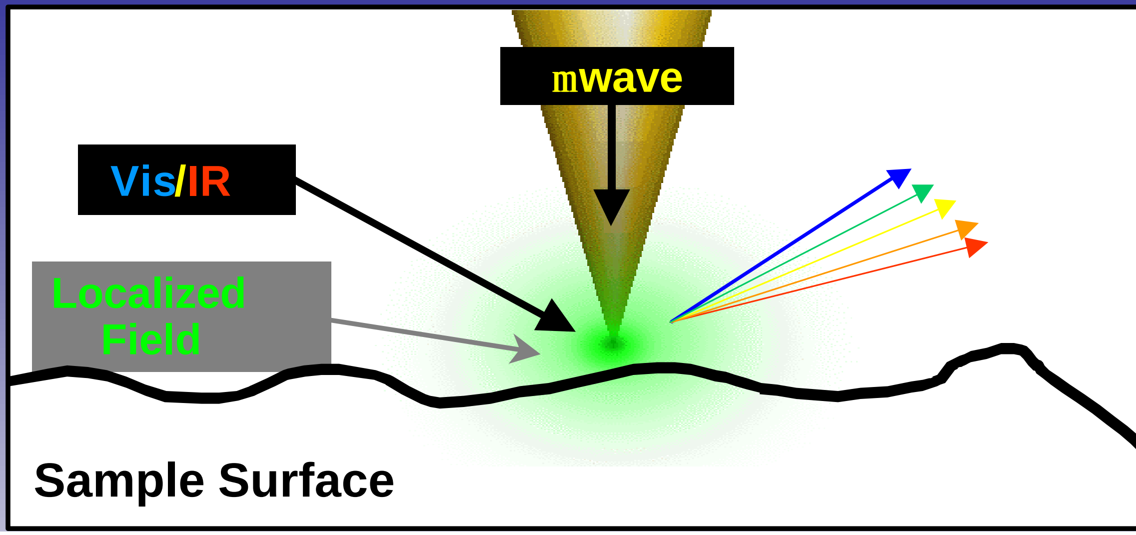
Probes of key materials properties:

➢Structural: phase, stress, …

➢Chemical: composition, impurities …

Integrated Multitasking/Multispectral Probe:

Þ evanescent probe in the near-field; sharpened metal tip »10 nm from surface

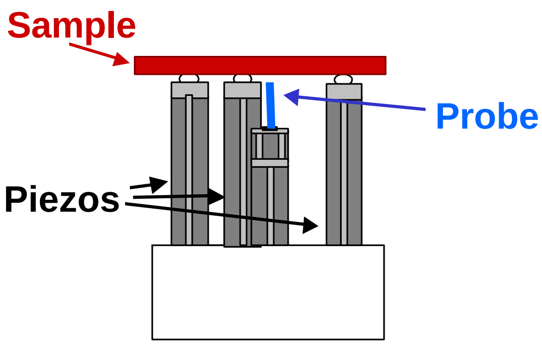


1) **Part of mwave cavity: materials performance by NSmM (Near-field Scanning Microwave Microscopy)**
   - dielectric loss spectroscopy.
   - probes local complex dielectric constant.

2) **External Vis/IR illumination: materials properties by aNSOM (apertureless Near-field Scanning Optical Microscopy)**
   - local field enhanced IR absorption/Raman scattering.
   - probes local chemical functionality/structure.

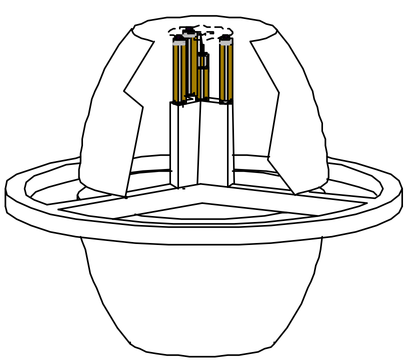
Instrumentation: fully-integrated system (not yet realized !)

Probe Positioning/Scanning:

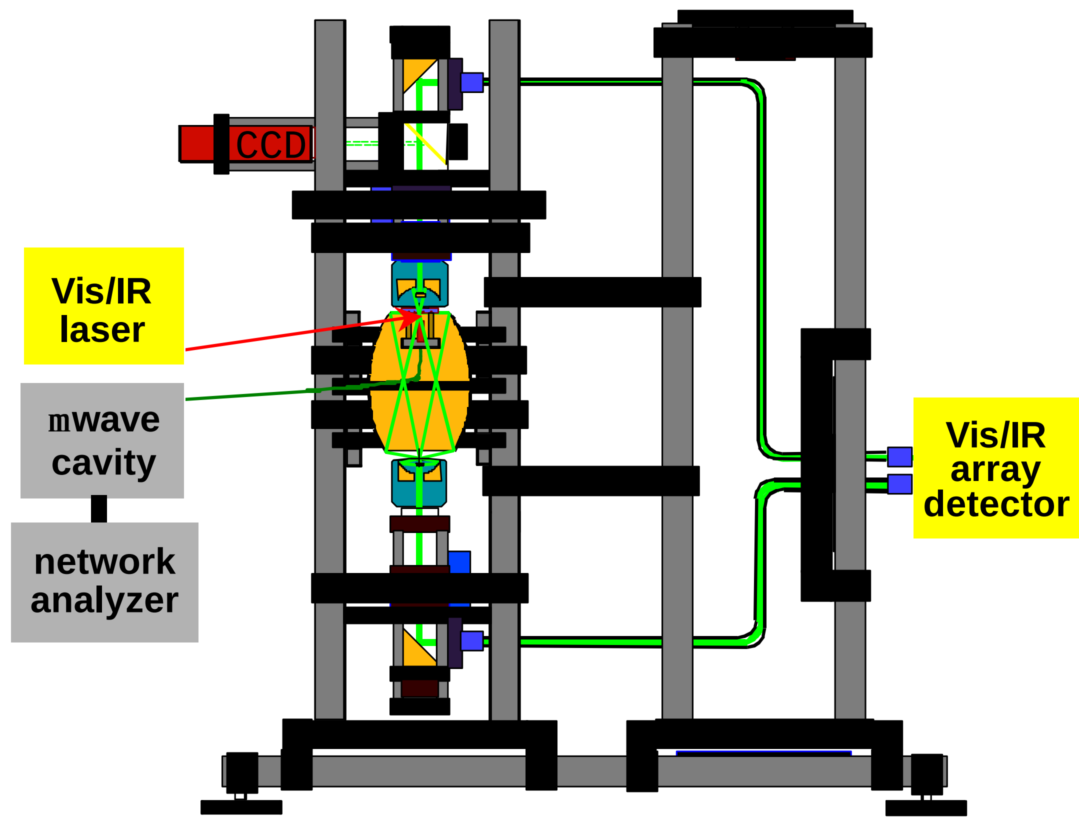


Shear Force Microscopy

Gold-coated ellipsoidal cavity for light collection:



Multitasking aNSOM/NSμM:

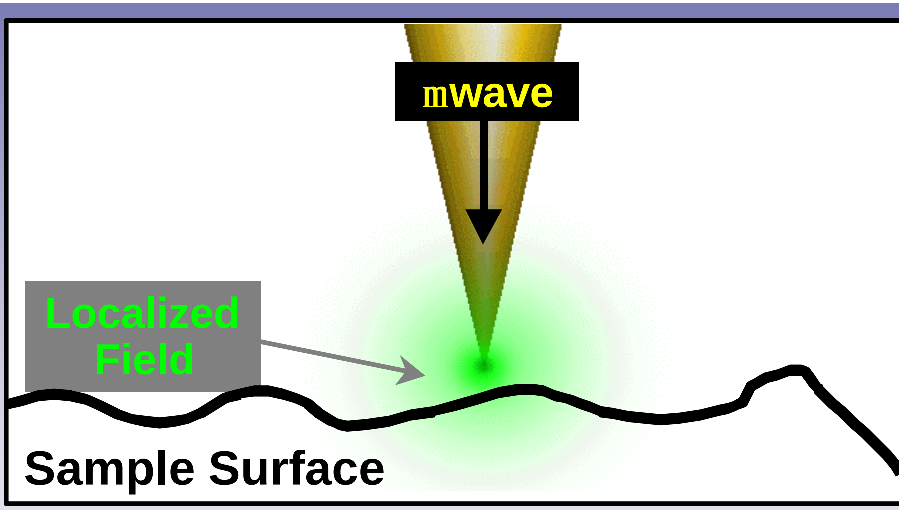


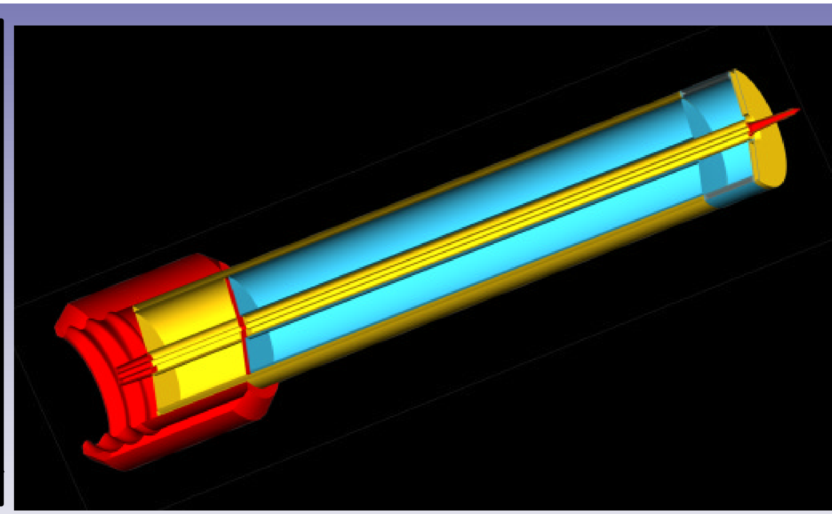
1) NSμM – Near-field Scanning Microwave Microscopy:

Developed in the mid ’90s:

- X.-D. Xiang – LBNL;   S.M. Anlage, F.C. Wellstood – U. Maryland
- Used by Xiang *et al.* for HTS/HTE of advanced oxide materials:

APL **72**, 2185 (’98); Mat.Sci. Eng. B. – Sol. **56**, 246 (’98); Biotech. Bioeng. **61**, 227 (’99).





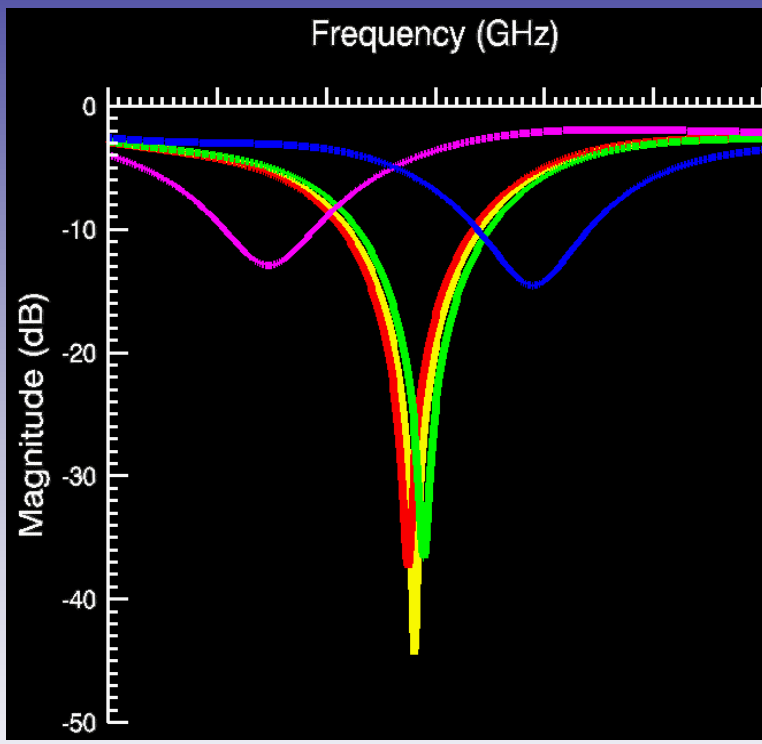
Advantages:

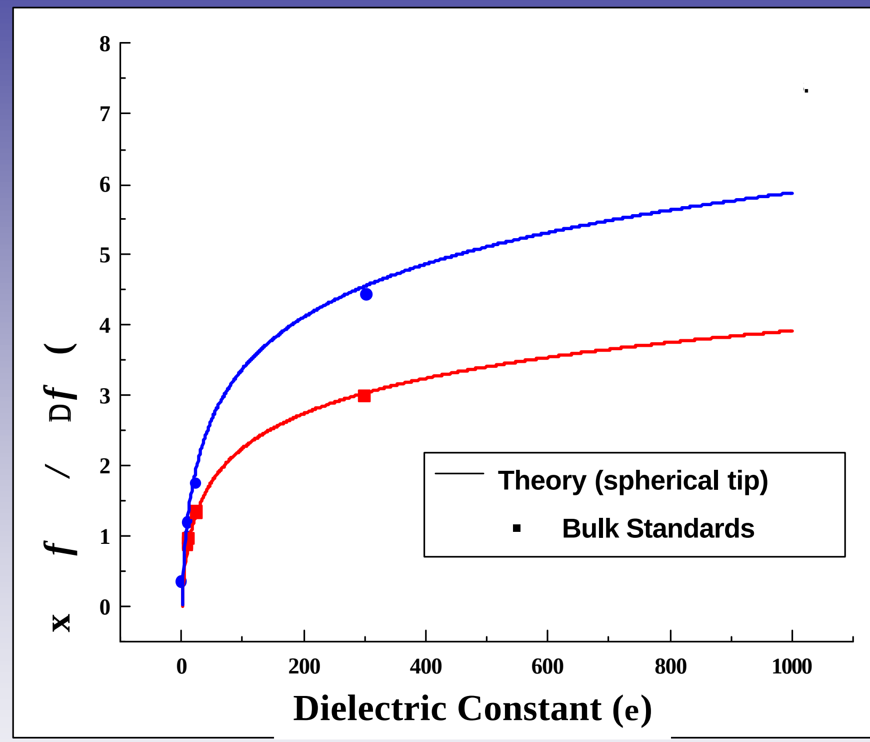
1) Non-contact
2) Sample geometry independent
3) Thin film samples

$\Rightarrow$ **Suitable for HTS/HTE.**

Dielectric Imaging: NSmM

- By measuring the frequency shift of the microscope’s resonant cavity, a dielectric response can be determined.



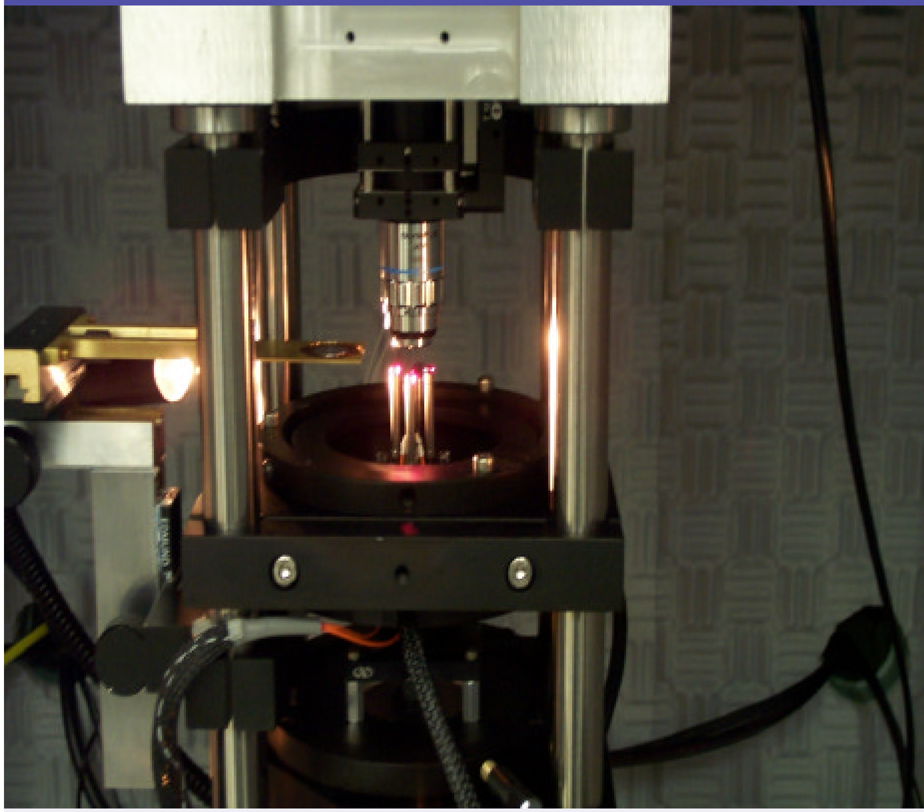


Spatial resolution Þ probe shape/radius; height from sample surface.

e precision Þ Df/f and cavity Q. 1

0

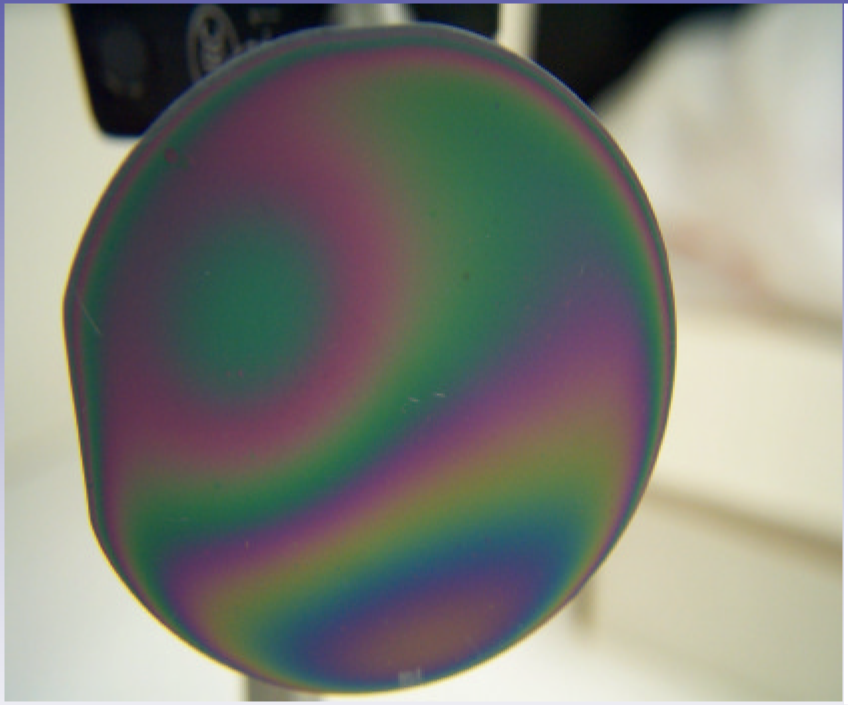
Near-field Scanning Microwave Microscope:

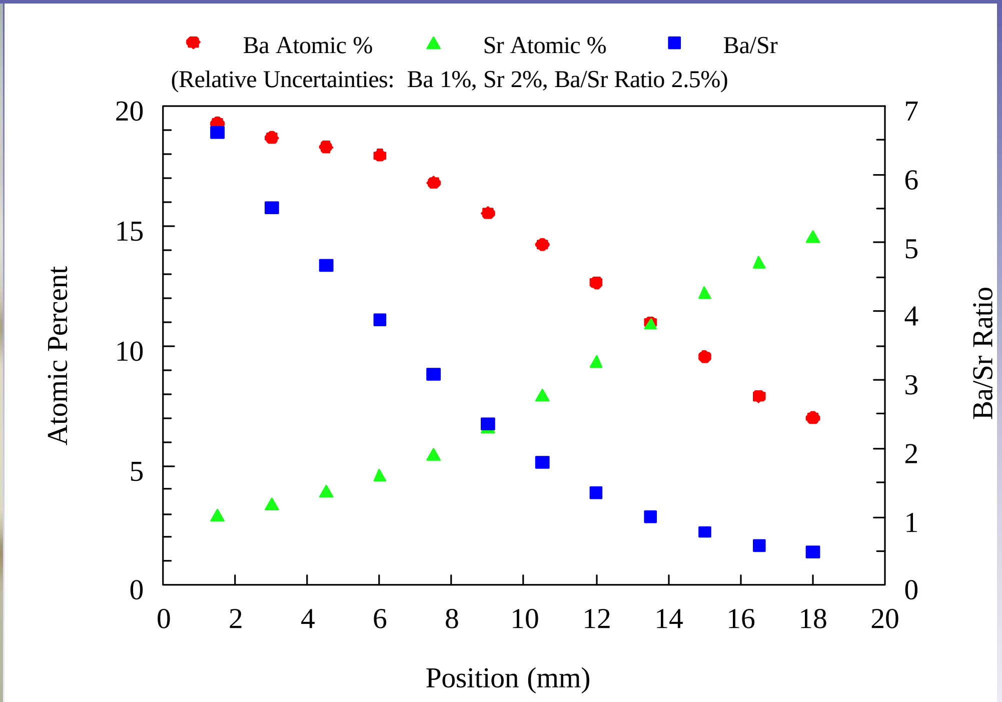


- **Diffraction-limitless resolution.**
  (~ 100 nm in xyz)
- **Shear-force feedback height regulation.**
  (typically 10-50 nm)
- **Broadband Measurement.**
  (45 MHz to 20 GHz)
- **Network analyzer: $\Delta f/f \approx 10^{-5}$ to 10^{-6}.**
  (ε to about 1-5 %)

Demonstration of NSmM:

- continuous compositional gradient Barium Strontium Titanate (BST) film.
- prepared by dual-beam pulsed laser deposition.

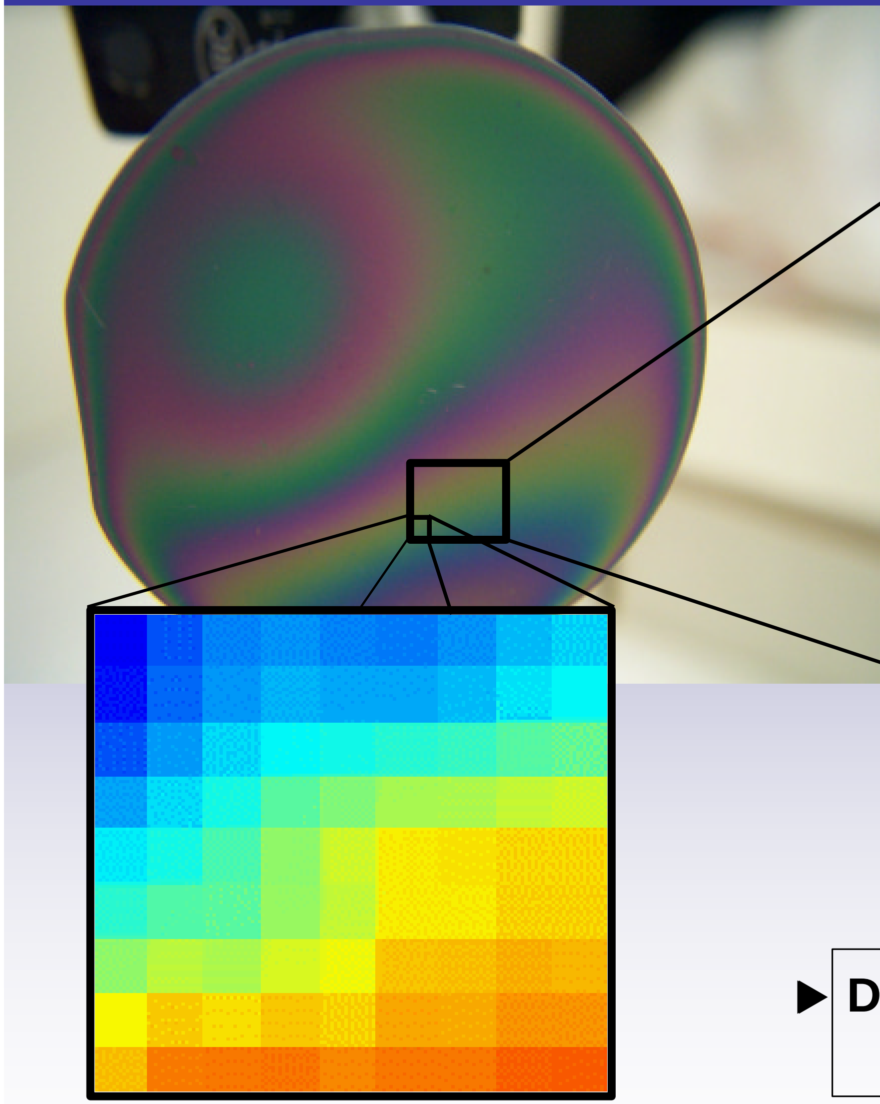


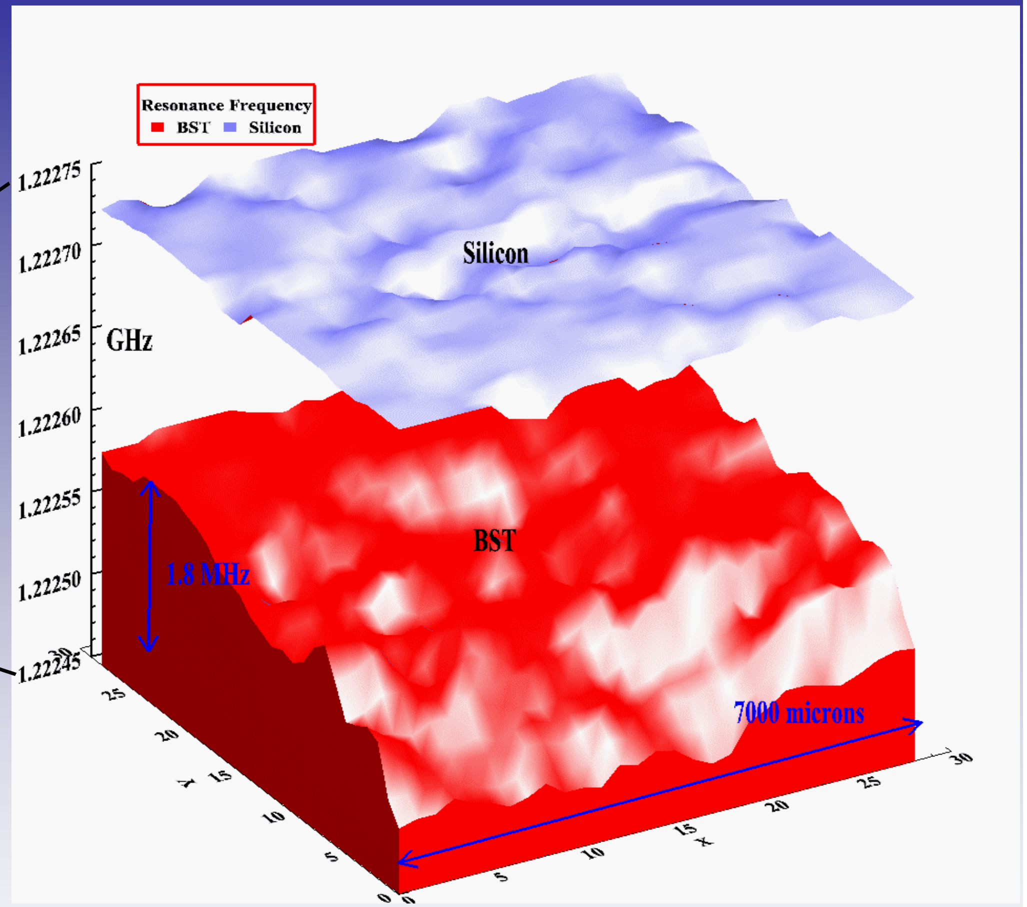


– Film thickness variation is evident.
– Quantitative analysis by spectrometric reflectometry.

– Compositional gradient quantified by wavelength-dispersive electron probe microanalysis.

Dielectric Response Mapping using NSmM:

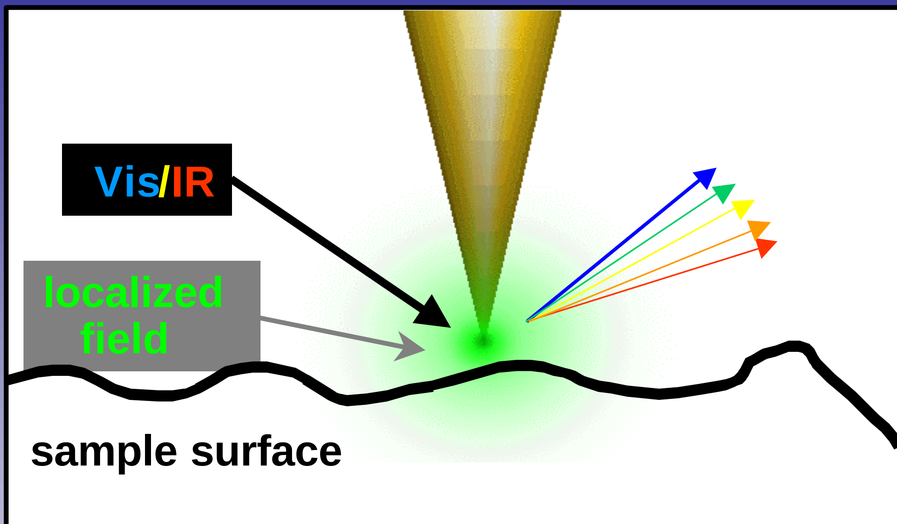




► Dielectric response dominated is by film thickness variations. ◄

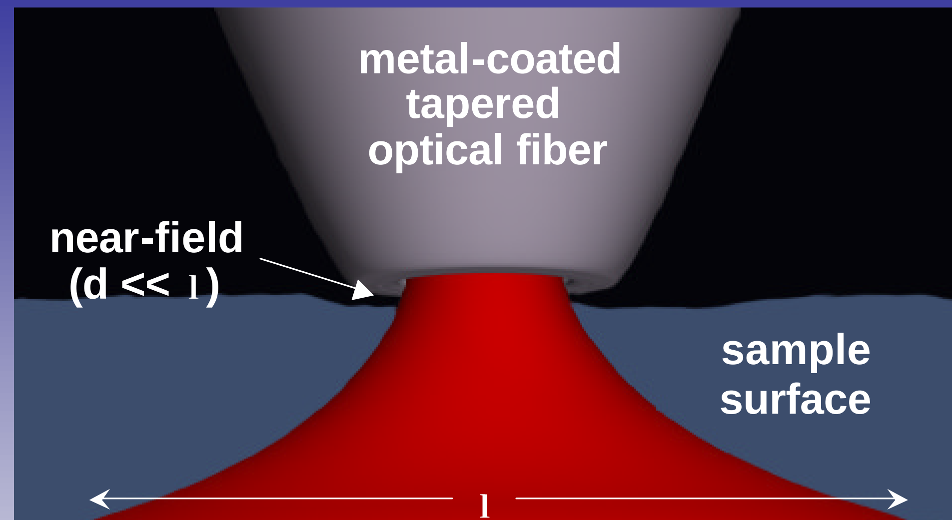
2) aNSOM - apertureless Near-field Scanning Optical Microscopy

aNSOM



Wickramasinghe, IBM '94; Kawata, Osaka U. '94

Fiber-coupled NSOM



Pohl, IBM '83; Lewis, Cornell U., '83

Similarities:

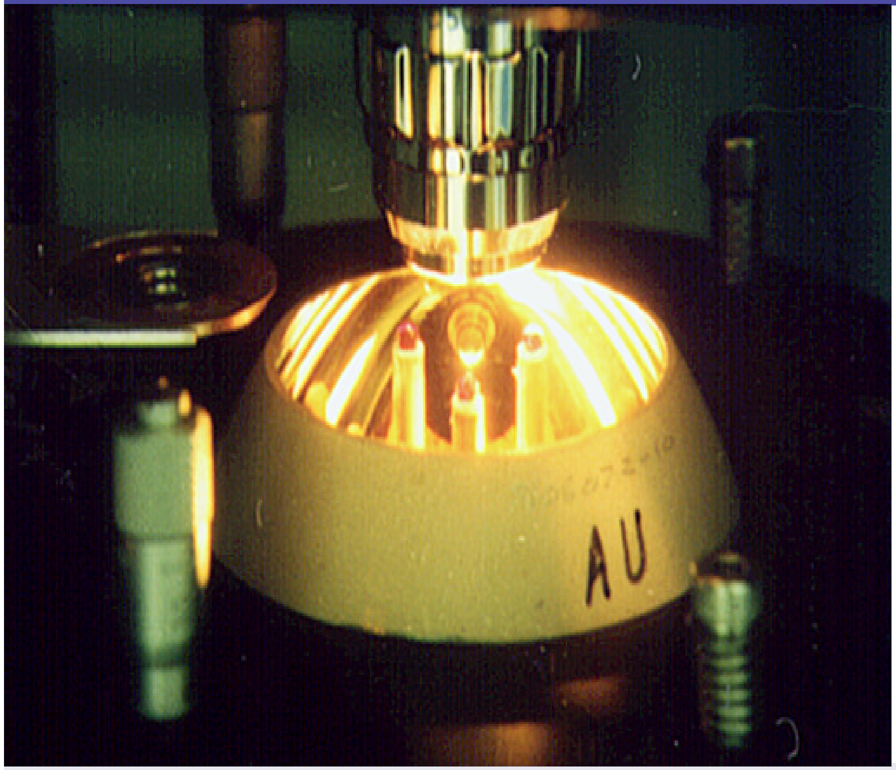
- near field scanned probe
- subwavelength resolution
- chemical imaging/spectroscopy

Differences:

- radiation coupling
- accessible wavelengths
- resolution: 1-2 nm vs ≈ 50 nm

NIST; chemical-imaging using Raman/IR fiber-coupled NSOM:
results illustrate expectations for aNSOM in multitasking application

Fiber-coupled NSOM:

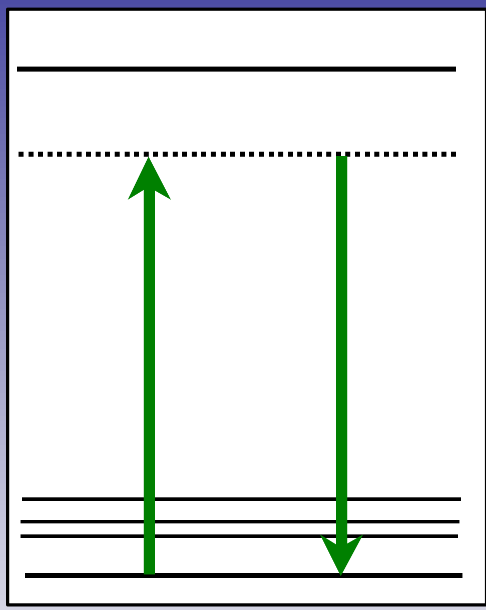


- Diffraction-limitless resolution.
  (~ 100 nm lateral)
- Shear-force feedback height regulation.
  (typically 10-50 nm)
- NUV to NIR *(0.3 – 1 μm; Raman)*
  IR *(2.5 – 10 μm; IR absorption)*
- Hyperspectral imaging.
  (spectrum at each spatial pixel)

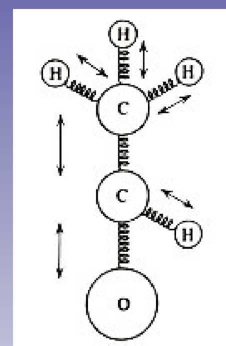
Raman Scattering Spectroscopy/NSOM:

Rayleigh Scattering
(Elastic Process)

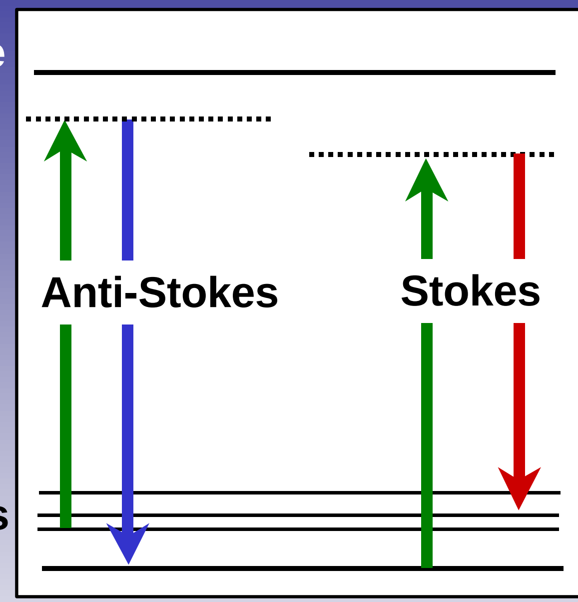
Raman Scattering
(Inelastic Process)



Molecular Excited State
(Virtual Excited State)



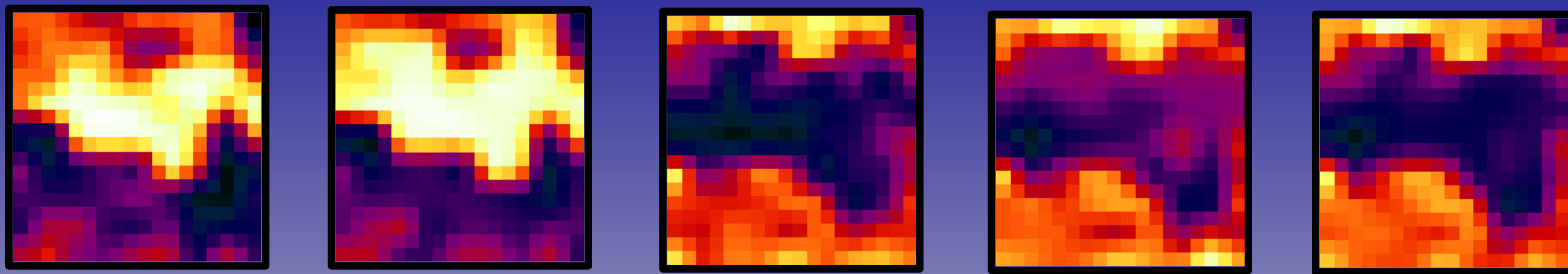
Vibrational Energy Levels
Molecular Ground State

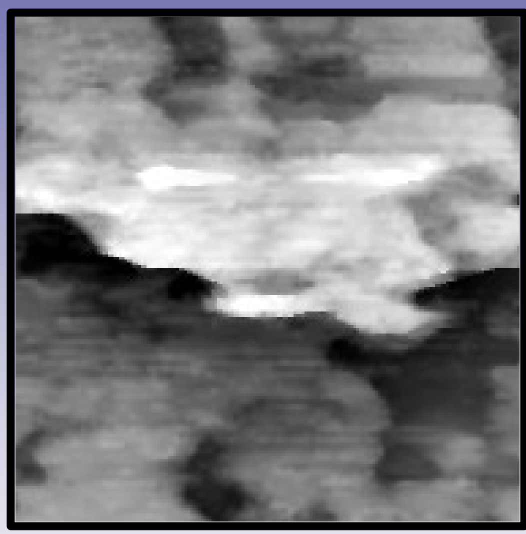


- **Highly specific chemical information/species and structure.**
- **Visible lasers/"standard" fiber optics.**

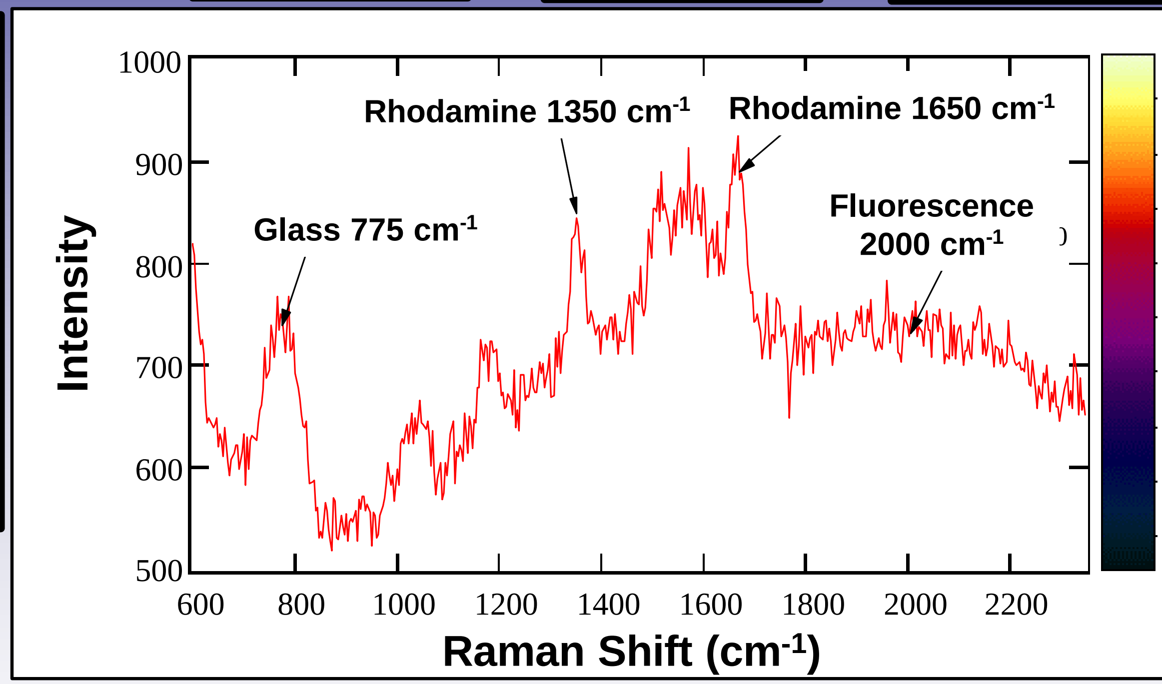
- **Inefficient process: only one in 10^{13} photons Raman scatter.**
- **NSOM probes have low throughput: ~ 10^{-5} - 10^{-6}.**

Rayleigh 514 nm | Glass (SiO_x) 775 cm^{-1} | Rhodamine-B 1350 cm^{-1} | Rhodamine-B 1650 cm^{-1} | Fluorescence 2000 cm^{-1}





Shear- force Image
3 μm x 3 μm



- **50 nm Ag film on glass, 0.7 μMol Rhodamine-B sol.**

Summary:

Program Goal - multitasking scanned probe for HTE/HTS:

- *simultaneously* obtain data for materials performance (dielectric constant) *and* materials properties (chemical composition/structure).
- targeting high-density (μm length scale) discrete samples and/or continuous compositional gradient materials libraries.

Integrated NSmM/aNSOM platform:

- not yet fully realized.
- have demonstrated independently the workability of Raman/IR fiber-coupled NSOM and NSμM on (nearly) identical platforms.
- work towards demonstrating Raman-based aNSOM and improving NSμM performance.

Research Team:

S.J. Stranick, C.A. Michaels and S.W. Robey:

NSμM and Raman/IR NSOM.

P.K. Schenck, D.L. Kaiser and B. Hockey:

BST library fabrication.

R.B. Marinenko and J.T. Armstrong:

Electron probe microanalysis.